

Ilya Shlyakhov

List of Publications by Year in descending order

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Version: 2024-02-01

12
papers

173
citations

1478458

6
h-index

1372553

10
g-index

12
all docs

12
docs citations

12
times ranked

247
citing authors

#	ARTICLE	IF	CITATIONS
1	Measurement of direct and indirect bandgaps in synthetic ultrathin MoS ₂ and WS ₂ films from photoconductivity spectra. Journal of Applied Physics, 2021, 129, .	2.5	5
2	Internal photoemission of electrons from 2D semiconductor/3D metal barrier structures. Journal Physics D: Applied Physics, 2021, 54, 295101.	2.8	1
3	Optical Transitions in Monolayer WS ₂ observed through Transient Photoconductivity in MIS Structures. Solid-State Electronics, 2021, 183, 108033.	1.4	0
4	Band alignment at interfaces of two-dimensional materials: internal photoemission analysis. Journal of Physics Condensed Matter, 2020, 32, 413002.	1.8	10
5	Ovonic Threshold Switching Ge _x Se _y Chalcogenide Materials: Stoichiometry, Trap Nature, and Material Relaxation from First Principles. Physica Status Solidi - Rapid Research Letters, 2020, 14, 1900672.	2.4	45
6	Material-Selective Doping of 2D TMDC through Al _x O _y Encapsulation. ACS Applied Materials & Interfaces, 2019, 11, 42697-42707.	8.0	37
7	Energy Band Alignment of a Monolayer MoS ₂ with SiO ₂ and Al ₂ O ₃ Insulators from Internal Photoemission. Physica Status Solidi (A) Applications and Materials Science, 2019, 216, 1800616.	1.8	11
8	Determination of energy thresholds of electron excitations at semiconductor/insulator interfaces using trap-related displacement currents. Microelectronic Engineering, 2019, 215, 110992.	2.4	3
9	A Sensitivity Map-Based Approach to Profile Defects in MIM Capacitors From $\frac{C}{V}$ & $\frac{C}{f}$ Measurements. IEEE Transactions on Electron Devices, 2019, 66, 1892-1898.	3.0	28
10	Band alignment at interfaces of synthetic few-monolayer MoS ₂ with SiO ₂ from internal photoemission. APL Materials, 2018, 6, .	5.1	17
11	Atomistic investigation of the electronic structure, thermal properties and conduction defects in Ge-rich Ge _x Se _{1-x} materials for selector applications. , 2017, , .		13
12	Oxygen-related defects: minority carrier lifetime killers in n-type Czochralski silicon wafers for solar cell application. Physica Status Solidi C: Current Topics in Solid State Physics, 2015, 12, 1108-1110.	0.8	3